

Description

The VSM3N10 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. This device is suitable for use in inverter and other applications.

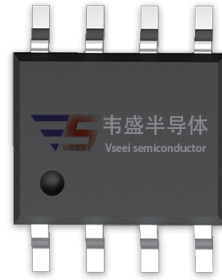
General Features

N-channel

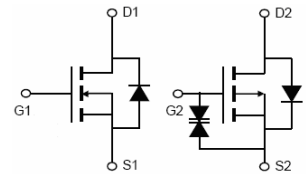
- $V_{DS} = 100V, I_D = 3A$
- $R_{DS(ON)} < 130m\Omega @ V_{GS}=10V$
- $R_{DS(ON)} < 140m\Omega @ V_{GS}=4.5V$
- High Power and current handling capability
- Lead free product is acquired

P-channel

- $V_{DS} = -100V, I_D = -3A$
- $R_{DS(ON)} < 200m\Omega @ V_{GS}=-10V$
- $R_{DS(ON)} < 230m\Omega @ V_{GS}=-4.5V$



SOP-8



Schematic Diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
VSM3N10-S8	VSM3N10	SOP-8	Ø330mm	12mm	4000 units

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

Parameter	Symbol	N-channel	P-channel	Unit
Drain-Source Voltage	V_{DS}	100	-100	V
Gate-Source Voltage	V_{GS}	± 20	± 20	V
Drain Current-Continuous (Note 2)	I_D	3	-3	A
		2.45	-2.45	A
Drain Current -Pulsed (Note 1)	I_{DM}	12	-12	A
Power Dissipation	P_D	2	2	W
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	-55 To 150	$^\circ C$

Thermal Characteristic

Parameter	Symbol	Typ	Max	Unit
Thermal Resistance, Junction-to-Ambient (Note 2) (N-channel)	$R_{\theta JA}$	-	62.5	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient (Note 2) (P-channel)	$R_{\theta JA}$	-	62.5	$^\circ C/W$

N-channel Electrical Characteristics (T_c=25°C unless otherwise noted)

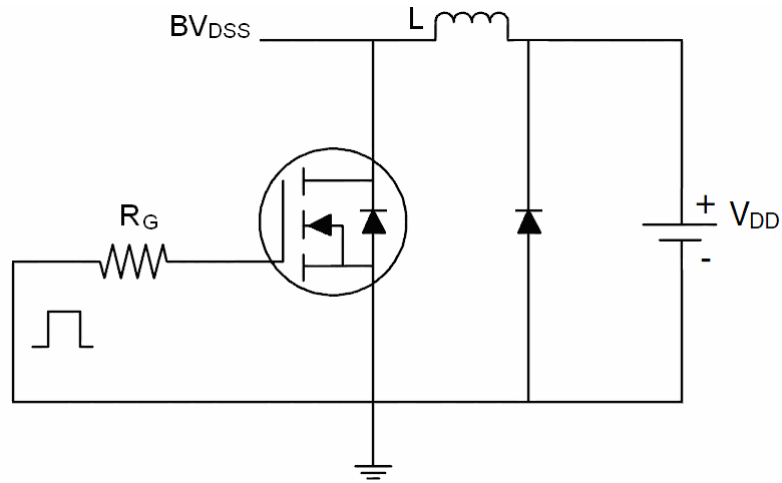
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	100	110	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =100V, V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
On Characteristics ^(Note 3)						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	1.0	1.5	2.0	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =3A	-	95	130	mΩ
		V _{GS} =4.5V, I _D =3A		100	140	
Forward Transconductance	g _{FS}	V _{DS} =5V, I _D =3A	3.5	-	-	S
Dynamic Characteristics ^(Note4)						
Input Capacitance	C _{iss}	V _{DS} =50V, V _{GS} =0V, F=1.0MHz	-	730	-	PF
Output Capacitance	C _{oss}		-	37	-	PF
Reverse Transfer Capacitance	C _{rss}		-	27	-	PF
Switching Characteristics ^(Note 4)						
Turn-on Delay Time	t _{d(on)}	V _{DD} =50V, R _L =15Ω V _{GS} =10V, R _G =2.5Ω	-	11	-	nS
Turn-on Rise Time	t _r		-	7.4	-	nS
Turn-Off Delay Time	t _{d(off)}		-	35	-	nS
Turn-Off Fall Time	t _f		-	9.1	-	nS
Total Gate Charge	Q _g	V _{DS} =50V, I _D =3A, V _{GS} =10V	-	21.5		nC
Gate-Source Charge	Q _{gs}		-	3.2	-	nC
Gate-Drain Charge	Q _{gd}		-	6	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage ^(Note 3)	V _{SD}	V _{GS} =0V, I _S =3A	-	-	1.2	V
Diode Forward Current ^(Note 2)	I _S		-	-	3	A
Reverse Recovery Time	t _{rr}	T _J = 25°C, I _F =3A di/dt = 100A/μs ^(Note3)	-	26		nS
Reverse Recovery Charge	Q _{rr}		-	27		nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

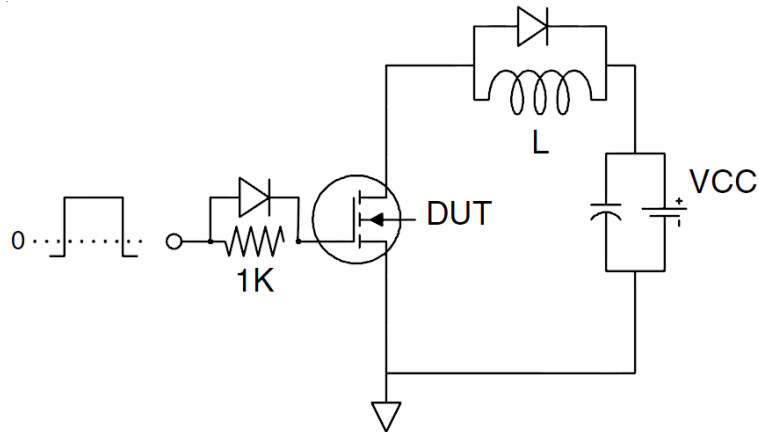
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. The value of R_{θJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any given application depends on the user's specific board design. Surface Mounted on FR4 Board, t ≤ 10 sec. The current rating is based on the t ≤ 10s thermal resistance rating.
3. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
4. Guaranteed by design, not subject to production .

Test Circuit

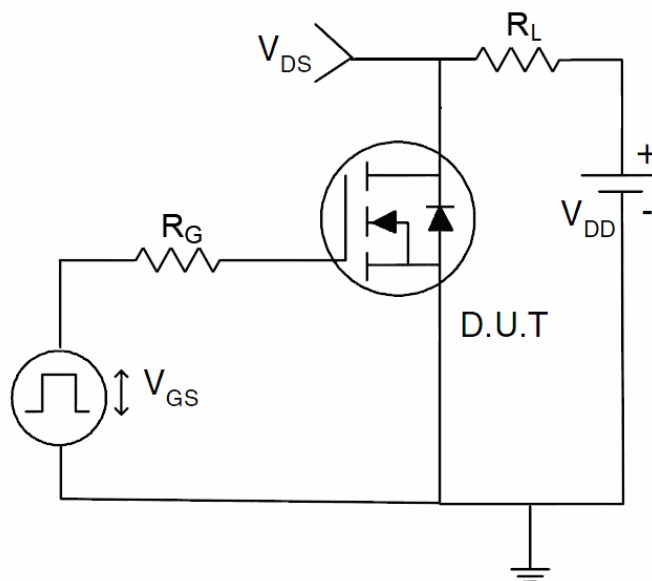
1) E_{AS} test Circuit



2) Gate charge test Circuit



3) Switch Time Test Circuit



N-channel Typical Electrical and Thermal Characteristics (Curves)

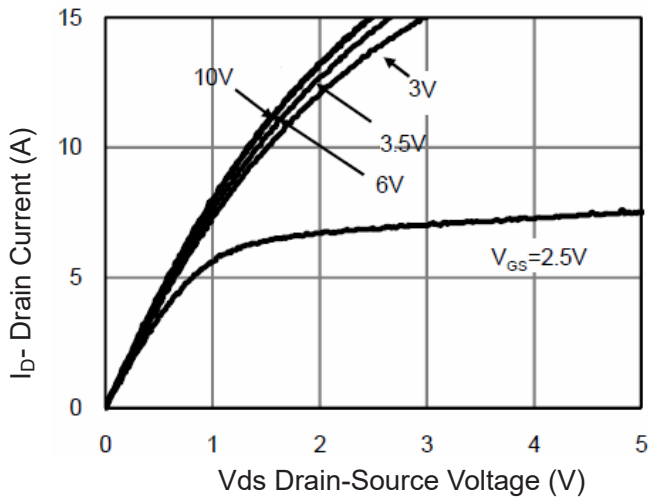


Figure 1 Output Characteristics

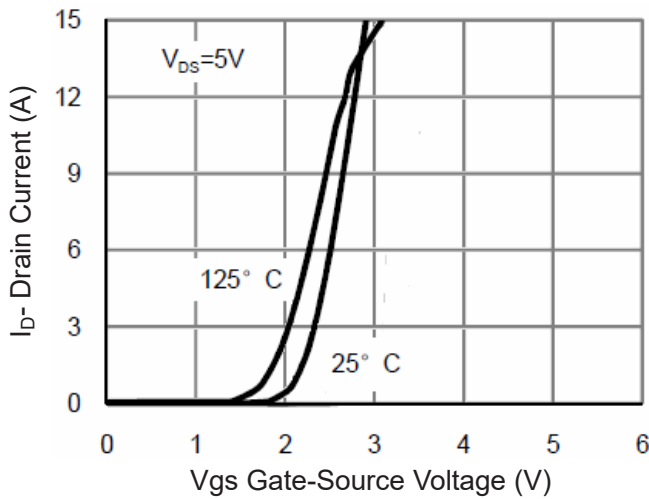


Figure 2 Transfer Characteristics

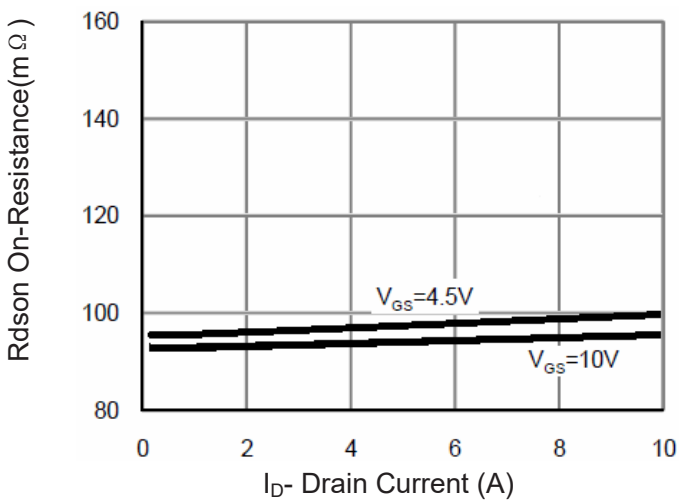


Figure 3 Rdson- Drain Current

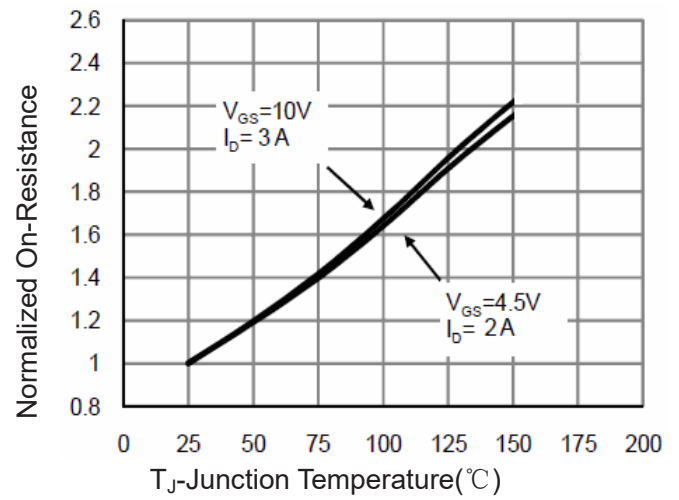


Figure 4 Rdson-Junction Temperature

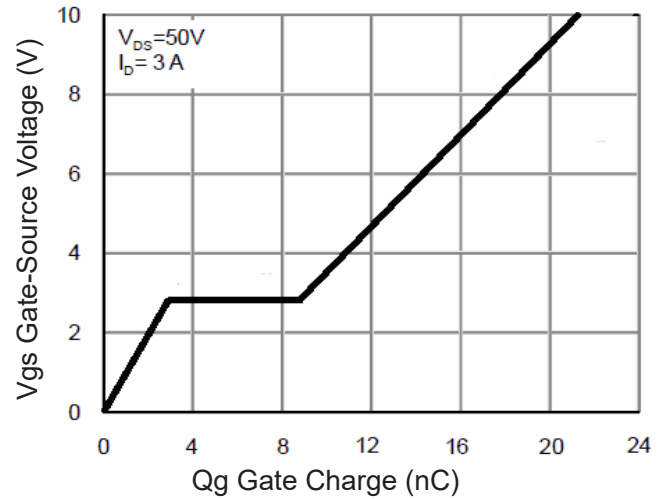


Figure 5 Gate Charge

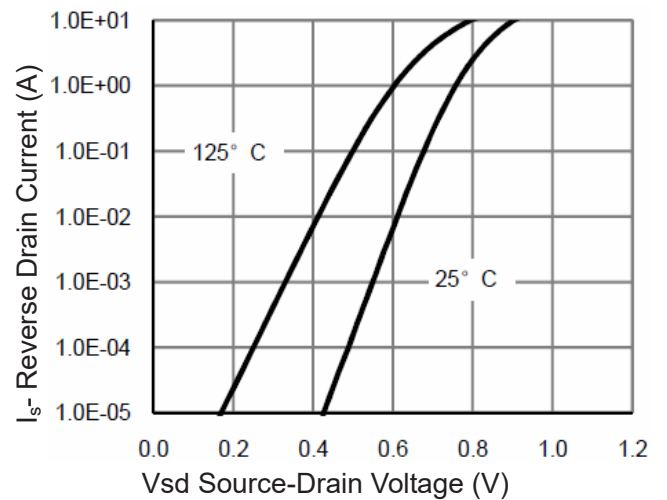
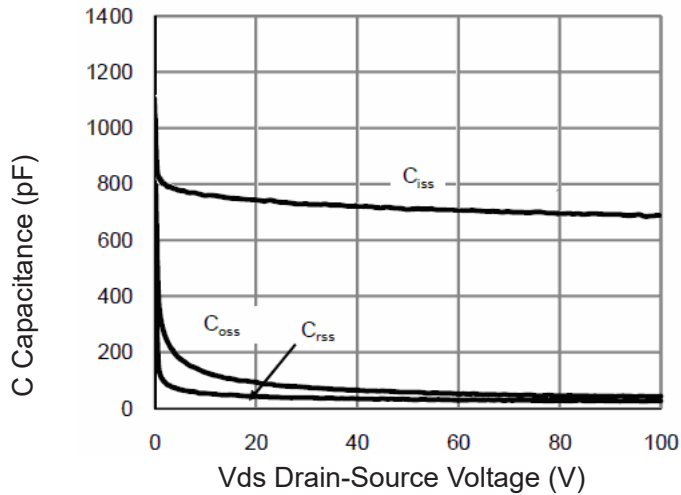
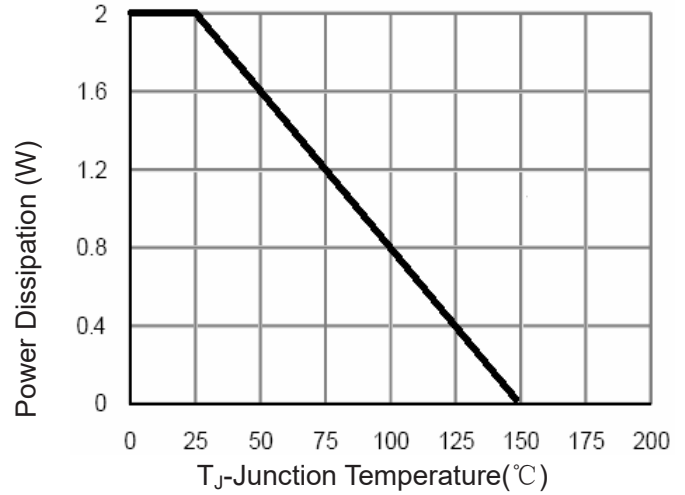
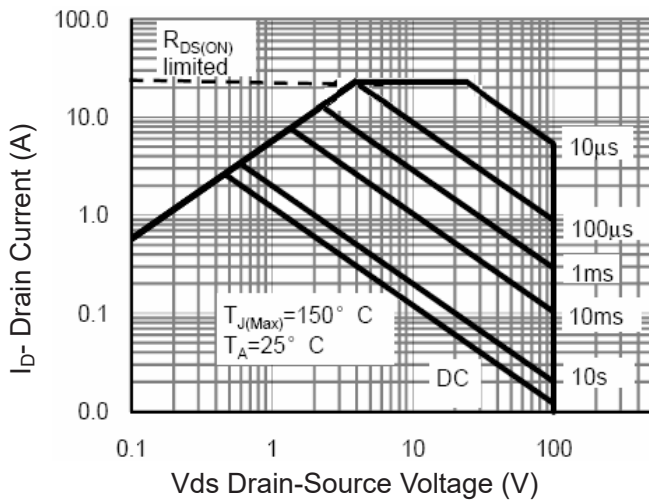
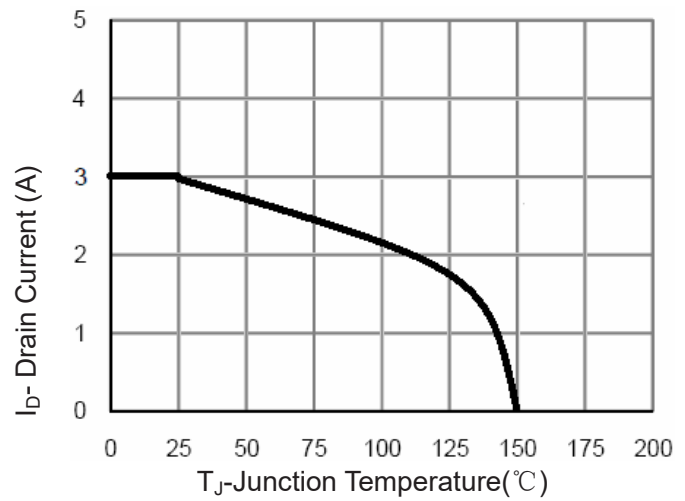
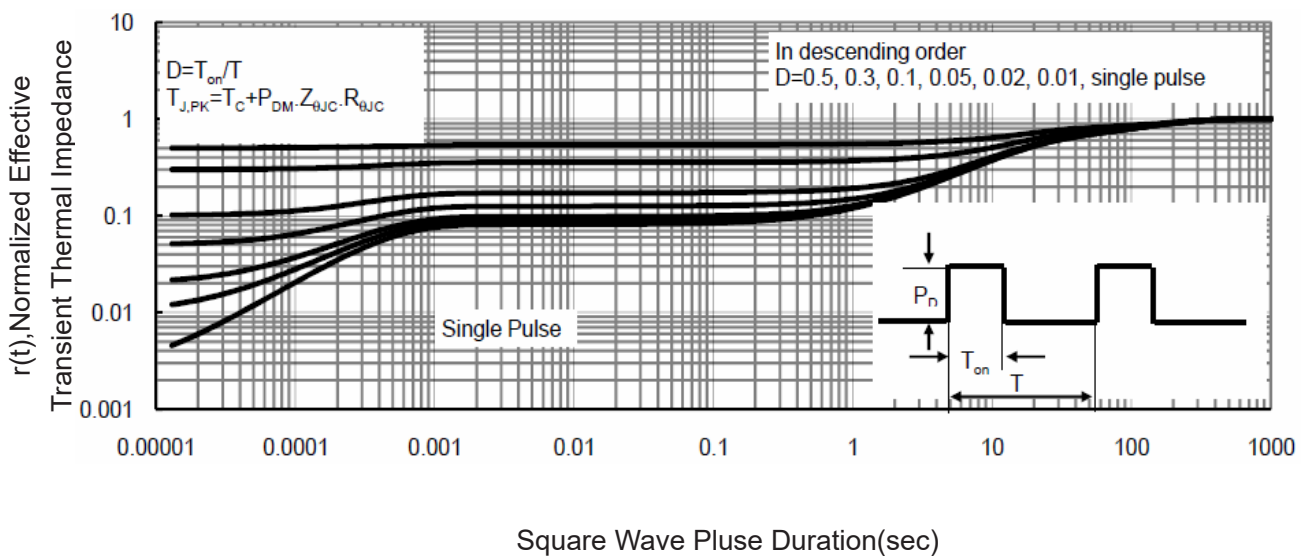


Figure 6 Source- Drain Diode Forward


Figure 7 Capacitance vs Vds

Figure 9 Power De-rating

Figure 8 Safe Operation Area

Figure 10 Current De-rating

Figure 11 Normalized Maximum Transient Thermal Impedance

P-channel Electrical Characteristics ($T_A=25^{\circ}\text{C}$ unless otherwise noted)

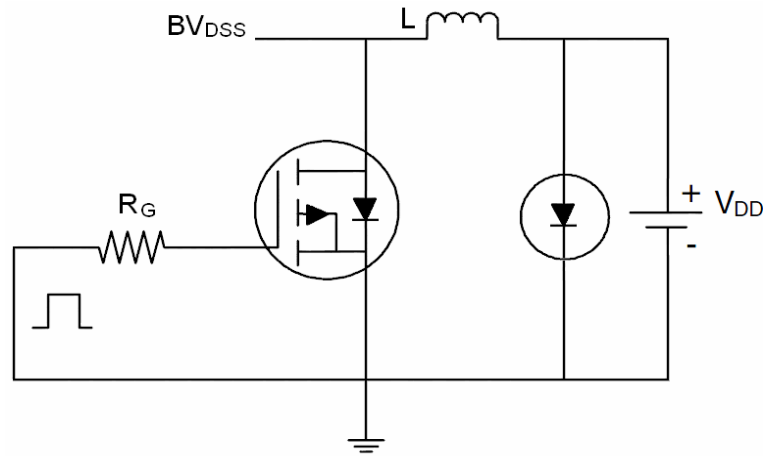
Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =-250μA	-100	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-100V, V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V	-	-	±10	μA
On Characteristics ^(Note 3)						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =-250μA	-1	-1.9	-3	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =-10V, I _D =-3A	-	170	200	mΩ
		V _{GS} =-4.5V, I _D =-2A		200	230	
Forward Transconductance	g _{FS}	V _{DS} =-5V, I _D =-3A	2	-	-	S
Dynamic Characteristics ^(Note4)						
Input Capacitance	C _{iss}	V _{DS} =-25V, V _{GS} =0V, F=1.0MHz	-	760	-	PF
Output Capacitance	C _{OSS}		-	260	-	PF
Reverse Transfer Capacitance	C _{rSS}		-	170	-	PF
Switching Characteristics ^(Note 4)						
Turn-on Delay Time	t _{d(on)}	V _{DD} =-50V, I _D =-3A V _{GS} =-10V, R _{GEN} =9Ω	-	14	-	nS
Turn-on Rise Time	t _r		-	18	-	nS
Turn-Off Delay Time	t _{d(off)}		-	50	-	nS
Turn-Off Fall Time	t _f		-	18	-	nS
Total Gate Charge	Q _g	V _{DS} =-50V, I _D =-3A, V _{GS} =-10V	-	25	-	nC
Gate-Source Charge	Q _{gs}		-	5	-	nC
Gate-Drain Charge	Q _{gd}		-	7	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage ^(Note 3)	V _{SD}	V _{GS} =0V, I _S =-3A	-	-	-1.2	V
Diode Forward Current ^(Note 2)	I _S	-	-	-	-3	A
Reverse Recovery Time	t _{rr}	T _J = 25°C, I _F =-3A di/dt = 100A/μs ^(Note3)	-	35	-	nS
Reverse Recovery Charge	Q _{rr}		-	46	-	nC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

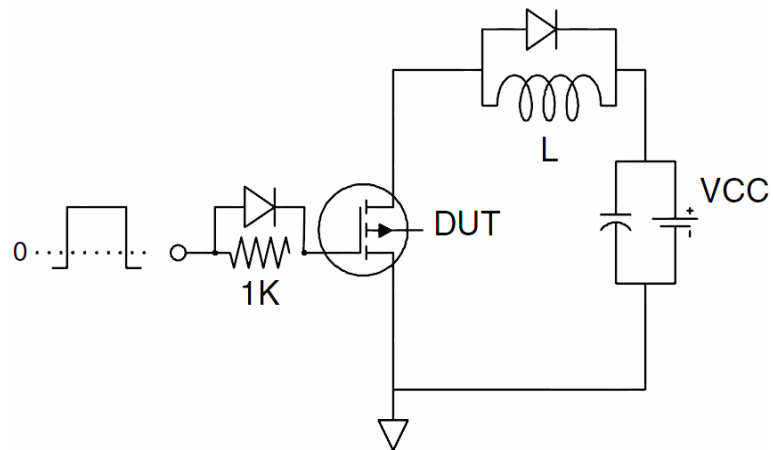
1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. E_{AS} condition: $T_J=25^{\circ}\text{C}, V_{DD}=-50V, V_G=-10V, L=0.5mH, R_g=25\Omega$

Test Circuit

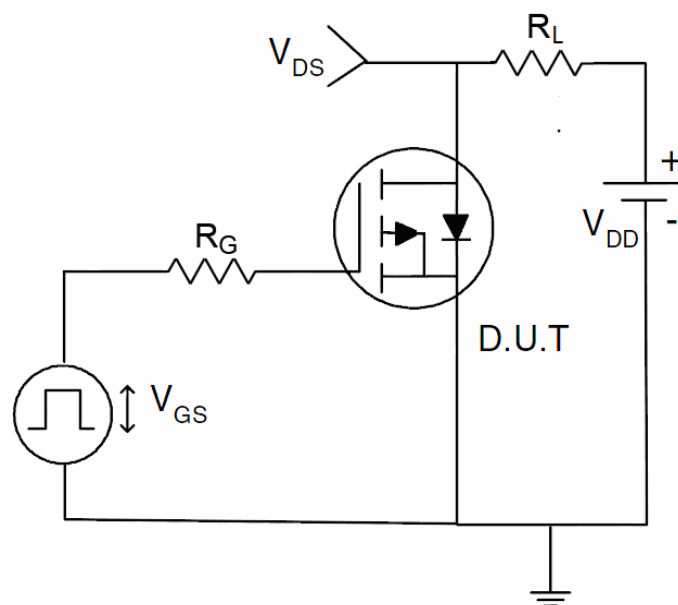
1) E_{AS} Test Circuit



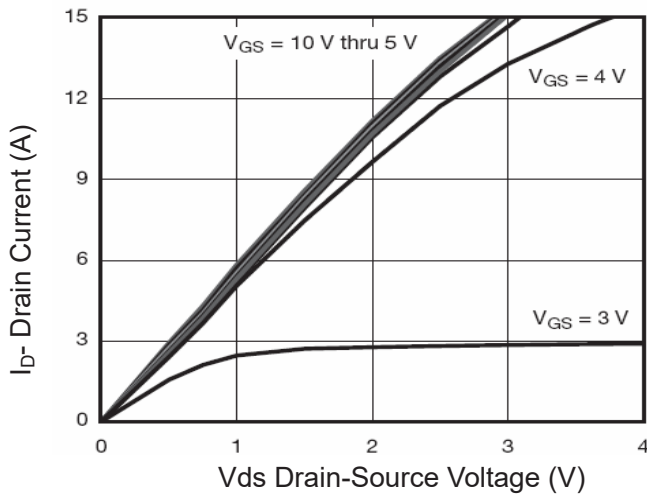
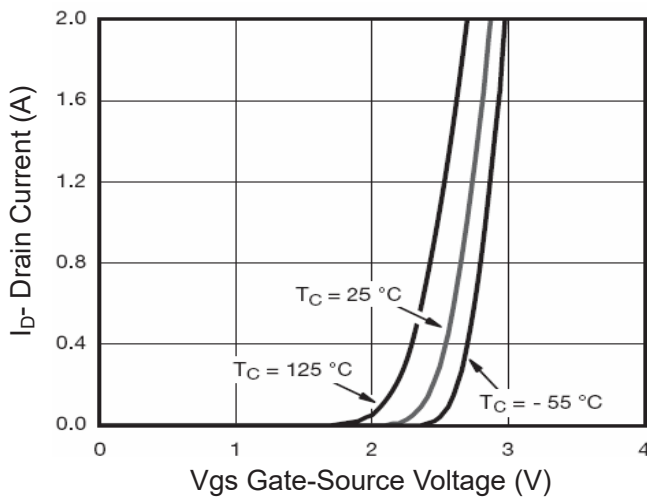
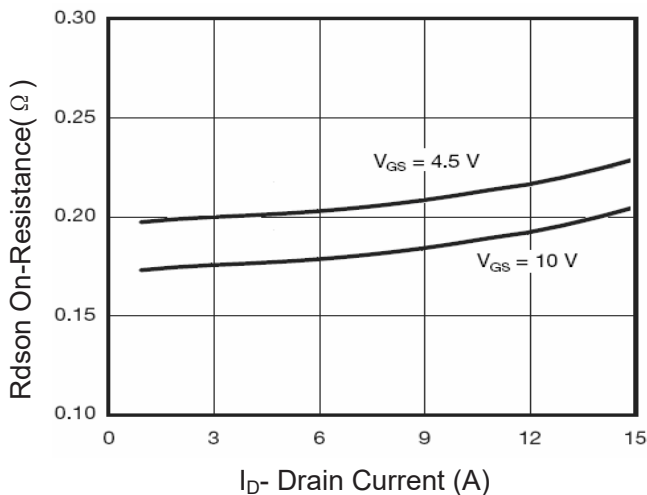
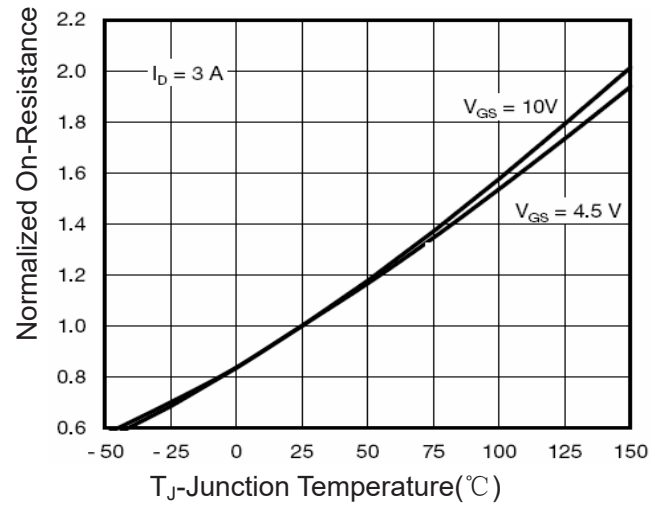
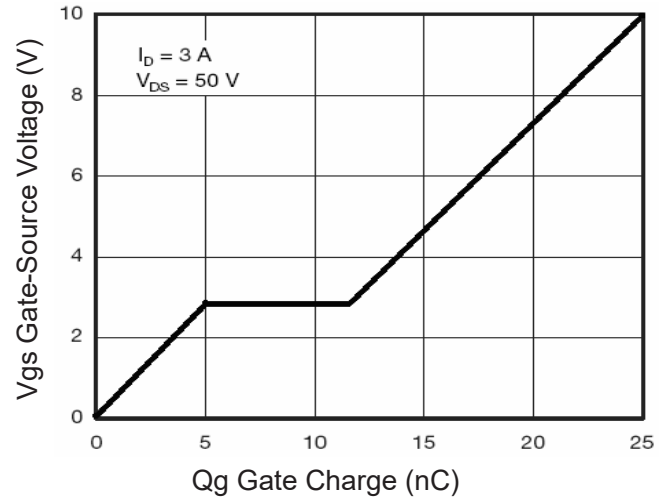
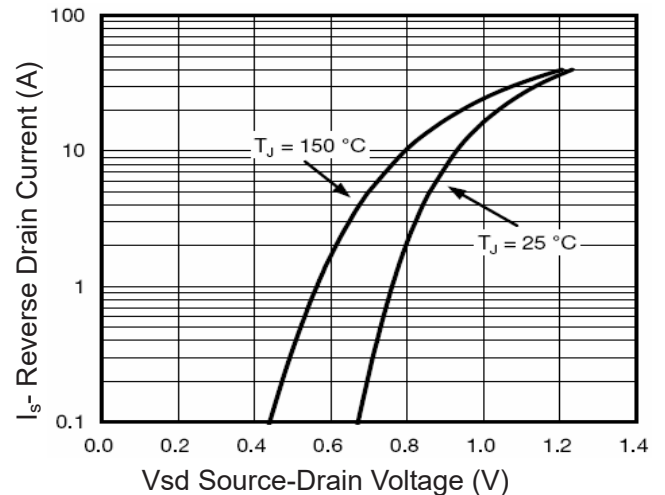
2) Gate Charge Test Circuit

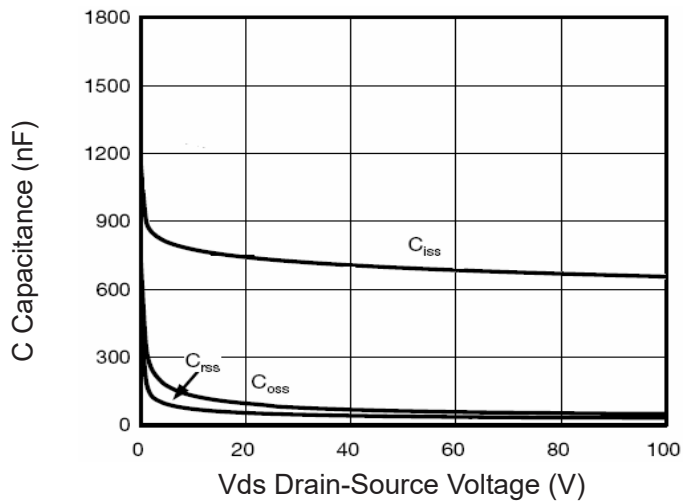
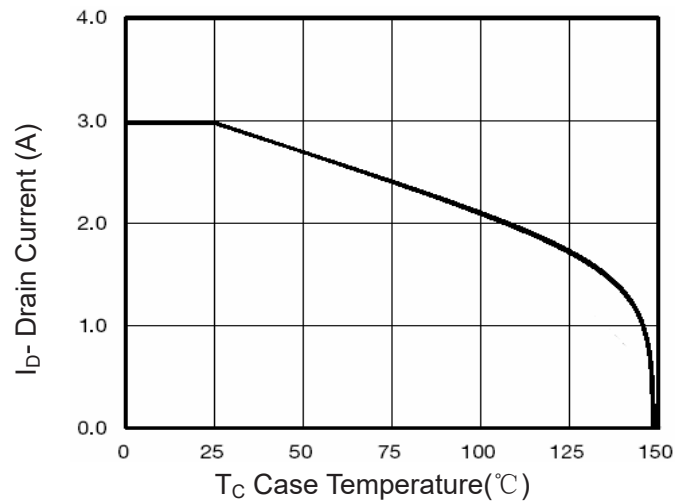
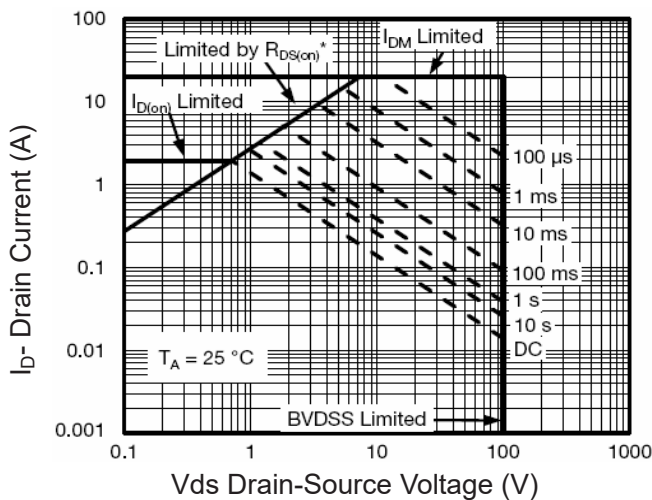
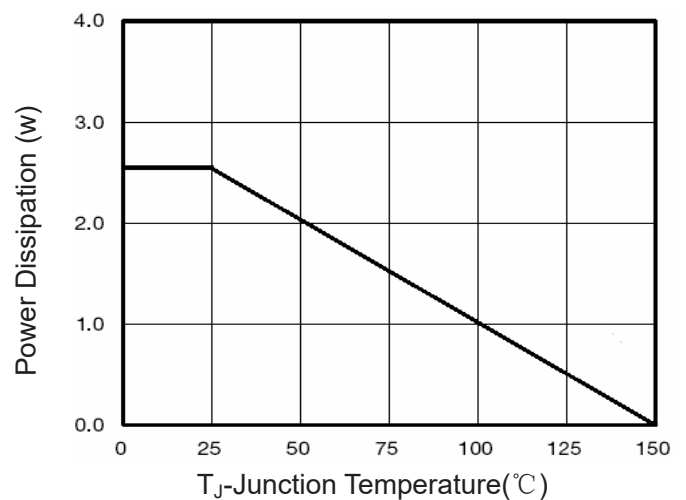
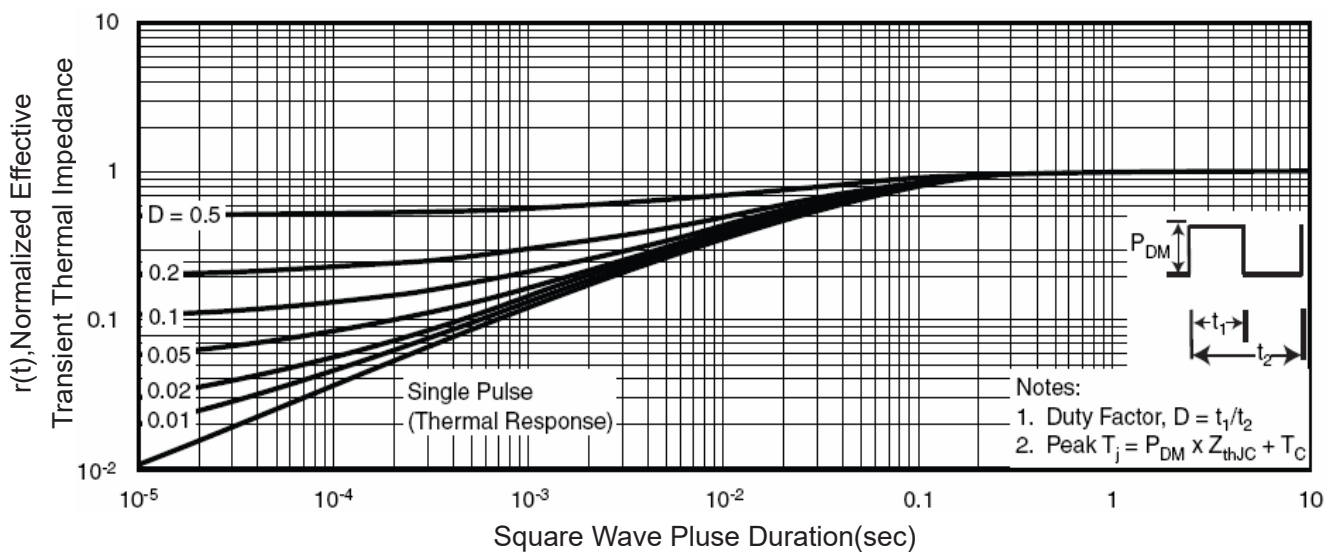


3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)


Figure 1 Output Characteristics

Figure 2 Transfer Characteristics

Figure 3 Rdson- Drain Current

Figure 4 Rdson-Junction Temperature

Figure 5 Gate Charge

Figure 6 Source- Drain Diode Forward


Figure 7 Capacitance vs Vds

Figure 9 Drain Current vs Case Temperature

Figure 8 Safe Operation Area

Figure 10 Power De-rating

Figure 11 Normalized Maximum Transient Thermal Impedance